

<b>Notice of References Cited</b>	Application/Control No. 09/912,558	Applicant(s)/Patent Under Reexamination WEIMER ET AL.
	Examiner Erik Kielin	Art Unit 2813

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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X	B	US-6,066,581 A	05-2000	Chivukula et al.	501/12
X	C	US-6,136,728 A	10-2000	Wang, Xiewen	438/773
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**NON-PATENT DOCUMENTS**

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	U	Van Zant, Microchip Fabrication, 4th ed. McGraw-Hill: New York, 2000, pp. 163-164.
	V	Van Zant, Microchip Fabrication, A Practical Guide to Semiconductor Processing, 3rd ed. McGraw-Hill: New York, 1997, pp. 157-160.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.